

# DATA SHEET

Model DHS100A15

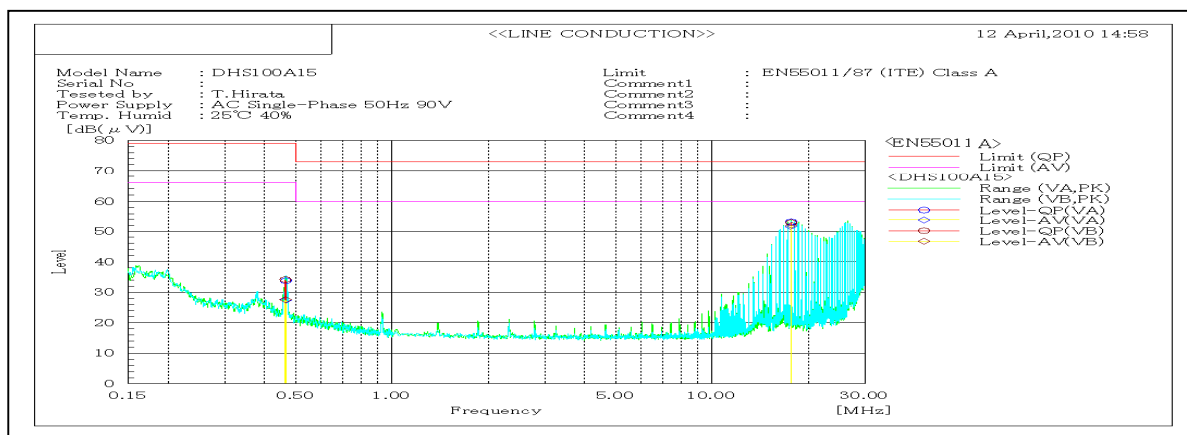
Date 26-Apr-10

Test EMI  
Line conduction & Radiated emission

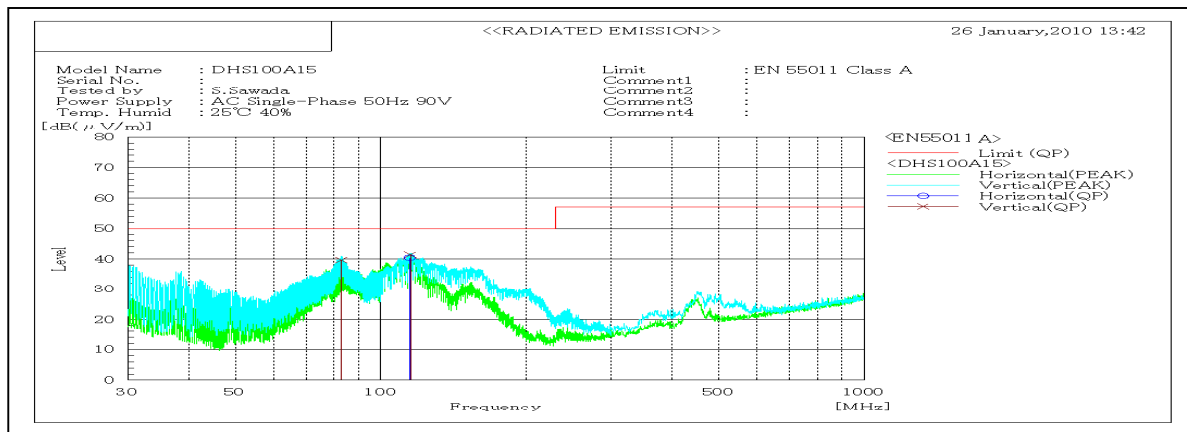
Temp. 25 degreeC

Humid. 40 %RH

Tested by T.Hirata



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.46442		VB	24.1	17.5	10	34.1	27.5	79	66	44.9	38.5	Pass	
0.46617		VA	23.7	17.4	10.1	33.8	27.5	79	66	45.2	38.5	Pass	
17.6755		VA	42.3	40.8	10.8	53.1	51.6	73	60	19.9	8.4	Pass	
17.6779		VB	41.8	41	11	52.8	52	73	60	20.2	8	Pass	

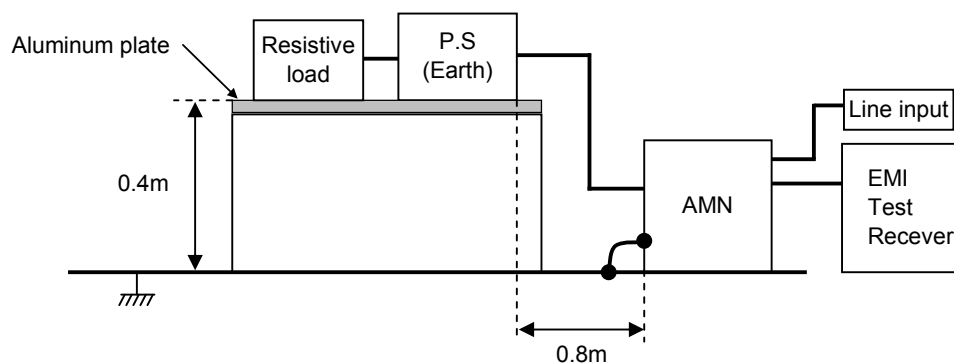


Frequency MHz	Harm	Polariz ation	Level Check	Stabili ty	Reading dB(μV)			Space Loss dB	Level dB(mW)			Limit dB(mW)	Limit dB(mW)	Limit dB(mW)	Margin dB			Pass/ Fail	Height cm	Angle deg	Remark
					QP	AV	PK		QP	AV	PK				QP	AV	PK				
82.701		V		Stable	63.8			-24.1	39.7			50			10.3			Pass	126	64	
115.228		V		Stable	61.1			-19.7	41.4			50			8.6			Pass	155	270	
114.786		H		Stable	60.2			-19.7	40.5			50			9.5			Pass	158	161	

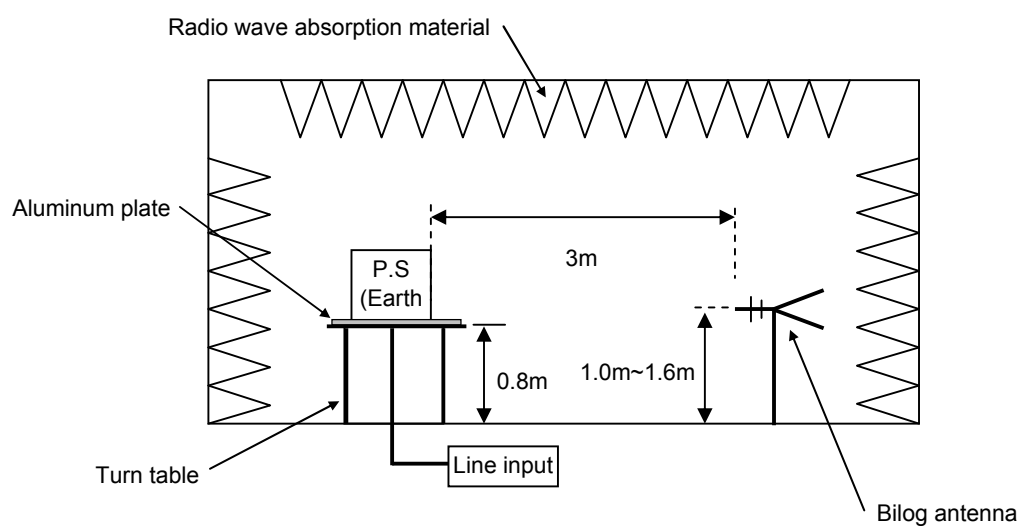
# DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

## 1. Line conduction



## 2. Radiated emission

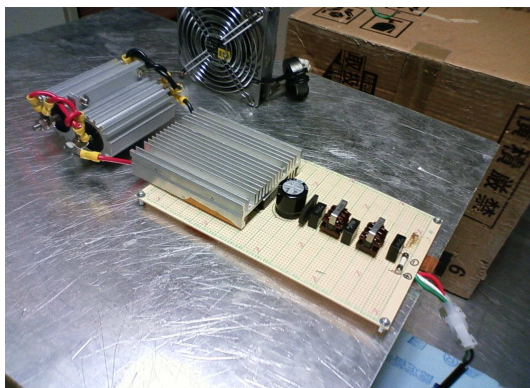


Test: EMI

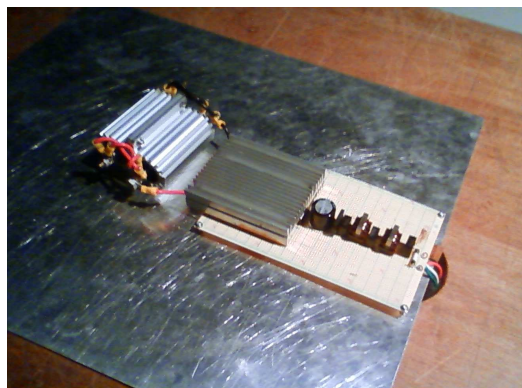
Model Name:DHS50A/DHS100A Series

## ○ Photographs of Test Set-Up

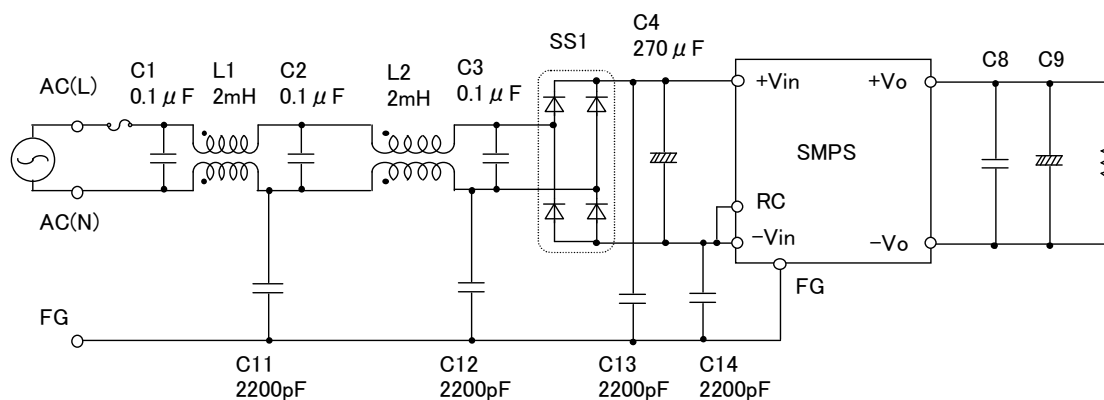
### LINE CONDUCTION



### RADIATED EMISSION



## ○ Test circuit



L1,L2	:	SC-05-200(NEC TOKIN)
SS1	:	D3SBA60(SINDENGEN)
C8	:	DHS50A24/DHS100A24 4.7 μ F
		Others 10 μ F
C9	:	DHS50A05/DHS100A05 2200 μ F
		DHS50A12/DHS100A12 470 μ F
		DHS50A15/DHS100A15 470 μ F
		DHS50A24/DHS100A24 220 μ F